

**Notice of References Cited**

Application/Control No.

10/535,689

Applicant(s)/Patent Under  
Reexamination  
ICHIKI ET AL.

Examiner

Tuan N. Nguyen

Art Unit

3751

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0005310 A1	01-2006	Nakamura et al.	004/420
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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